
**Surface chemical analysis —
Secondary-ion mass spectrometry —
Repeatability and constancy of the
relative-intensity scale in static
secondary-ion mass spectrometry**

*Analyse chimique des surfaces — Spectrométrie de masse des ions
secondaires — Répétabilité et constance de l'échelle des intensités
relatives en spectrométrie statique de masse des ions secondaires*



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Tel. + 41 22 749 01 11
Fax + 41 22 749 09 47
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